NEC

# SILICON TRANSISTOR
# 2SA675

## PNP SILICON EPITAXIAL TRANSISTOR
## FOR DRIVING FLUORESCENT INDICATOR PANNEL

The 2SA675 is a resin sealed mold transistor and is ideal for dynamic drivers of counting indicator pannel such as fluorescent indicator pannel due to high voltage.

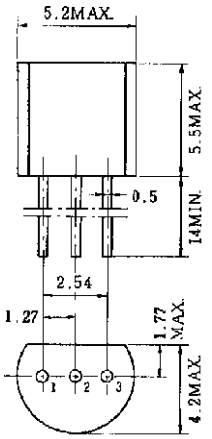
- High voltage
  $V_{CBO}$ > –80 V, $V_{CER}$ > –80 V
- Excellent linearity for current of DC current gain

### ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

| Parameter | Symbol | Ratings | Unit |
|---|---|---|---|
| Collector to base voltage | $V_{CBO}$ | –80 | V |
| Collector to emitter voltage | $V_{CER}$ * | –80 | V |
| Emitter to base voltage | $V_{EBO}$ | –5.0 | V |
| Collector current | $I_C$ | –100 | mA |
| Total power dissipation | $P_T$ | 250 | mW |
| Junction temperature | $T_j$ | 125 | °C |
| Storage temperature | $T_{stg}$ | –55 to +125 | °C |

* $R_{BE}$ = 30 kΩ

### PACKAGE DRAWING (UNIT: mm)




Electrode Connection
1. Emitter
2. Collector
3. Base
EIAJ : SC–43
JEDEC : TO–92
IEC : PA33

### ELECTRICAL CHARACTERISTICS (Ta = 25°C)

| Parameter | Symbol | Conditions | MIN. | TYP. | MAX. | Unit |
|---|---|---|---|---|---|---|
| Collector cutoff current | $I_{CBO}$ | $V_{CB}$ = –60 V, $I_E$ = 0 | | | –1.0 | μA |
| Emitter cutoff current | $I_{EBO}$ | $V_{EB}$ = –3.0 V, $I_C$ = 0 | | | –1.0 | μA |
| DC current gain | $h_{FE1}$ | $V_{CE}$ = –3.0 V, $I_C$ = –1.0 mA | 60 | 120 | | |
| DC current gain | $h_{FE2}$ | $V_{CE}$ = –3.0 V, $I_C$ = –20 mA | 50 | 120 | 300 | |
| Collector saturation voltage | $V_{CE(sat)}$ | $I_C$ = –20 mA, $I_B$ = –1.0 mA | | –0.10 | –1.50 | V |
| Base saturation voltage | $V_{BE(sat)}$ | $I_C$ = –20 mA, $I_B$ = –1.0 mA | | –0.74 | –1.20 | V |
| Gain bandwidth product | $f_T$ | $V_{CE}$ = –6.0 V, $I_E$ = 10 mA | 100 | 170 | | MHz |
| Output capacitance | $C_{ob}$ | $V_{CB}$ = –10 V, $I_E$ = 0, f = 1.0 MHz | | 4.5 | 10 | pF |
| Storage time | $t_{stg}$ | Refer to the test circuit. | | 0.5 | 1.0 | μs |



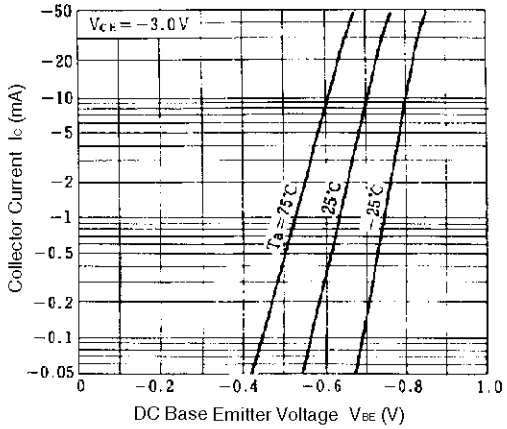
Document No. D16146EJ3V0DS00
Date Published April 2002 N CP(K)
Printed in Japan

## $h_{FE}$ CLASSIFICATION

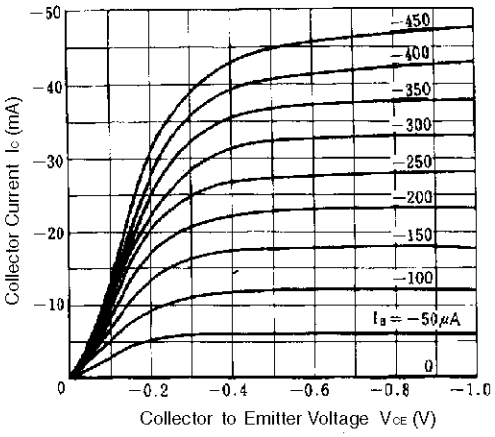
| Marking | L | K | U |
|---|---|---|---|
| $h_{FE2}$ | 50 to 125 | 80 to 200 | 120 to 300 |

## TYPICAL CHARACTERISTICS (Ta = 25°C)

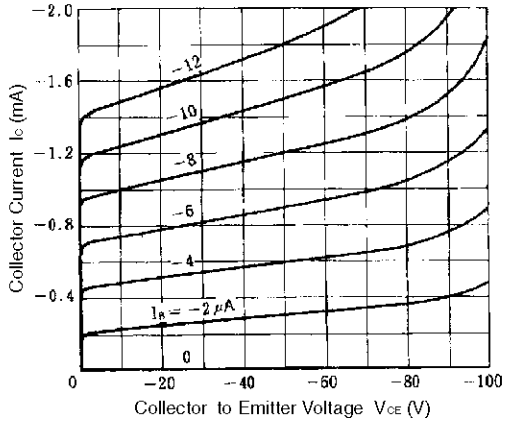
COLLECTOR CURRENT vs.
BASE TO EMITTER VOLTAGE



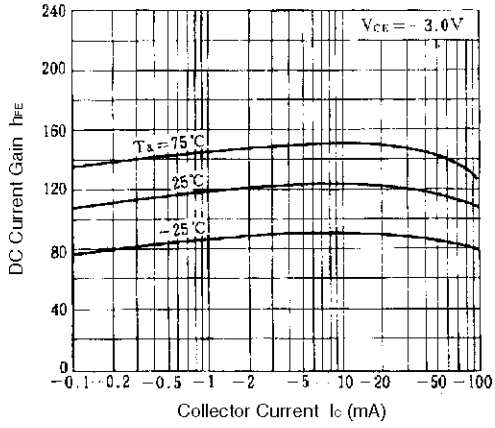

COLLECTOR CURRENT vs.
COLLECTOR TO EMITTER VOLTAGE



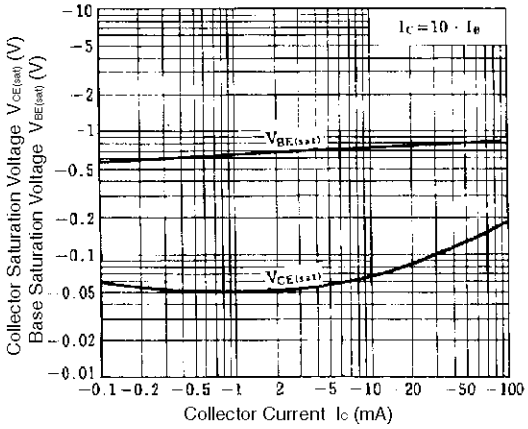

COLLECTOR CURRENT vs.
COLLECTOR TO EMITTER VOLTAGE



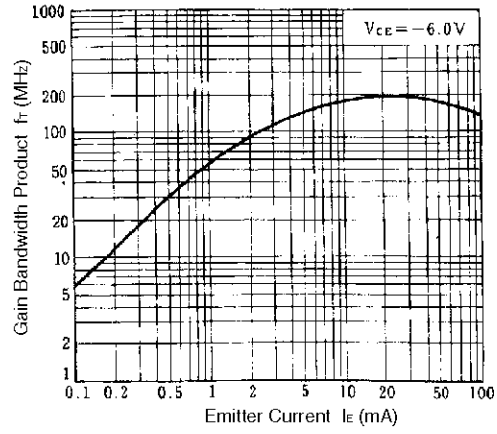

DC CURRENT GAIN vs.
COLLECTOR CURRENT

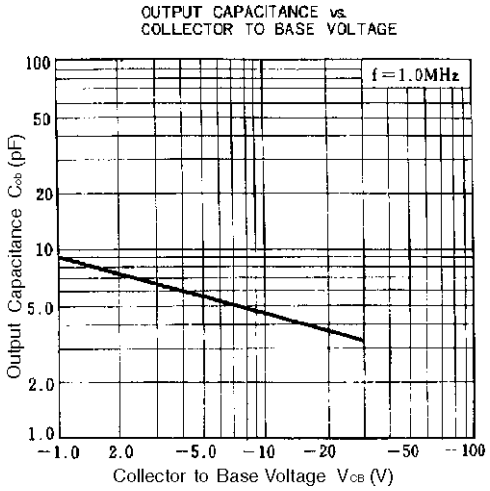



BASE AND COLLECTOR SATURATION
VOLTAGE vs. COLLECTOR CURRENT

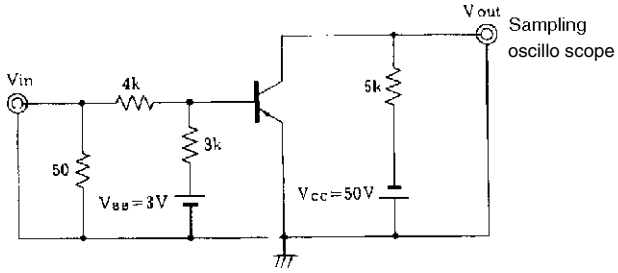


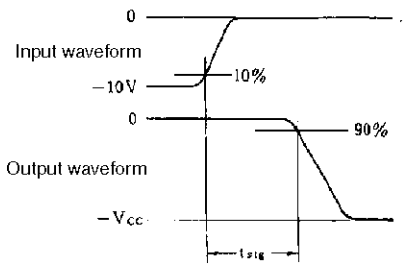

GAIN BANDWIDTH PRODUCT vs.
EMITTER CURRENT






## SWITCHING TIME TEST CIRCUIT



- **The information in this document is current as of July, 2001. The information is subject to change without notice. For actual design-in, refer to the latest publications of NEC's data sheets or data books, etc., for the most up-to-date specifications of NEC semiconductor products. Not all products and/or types are available in every country. Please check with an NEC sales representative for availability and additional information.**
- No part of this document may be copied or reproduced in any form or by any means without prior written consent of NEC. NEC assumes no responsibility for any errors that may appear in this document.
- NEC does not assume any liability for infringement of patents, copyrights or other intellectual property rights of third parties by or arising from the use of NEC semiconductor products listed in this document or any other liability arising from the use of such products. No license, express, implied or otherwise, is granted under any patents, copyrights or other intellectual property rights of NEC or others.
- Descriptions of circuits, software and other related information in this document are provided for illustrative purposes in semiconductor product operation and application examples. The incorporation of these circuits, software and information in the design of customer's equipment shall be done under the full responsibility of customer. NEC assumes no responsibility for any losses incurred by customers or third parties arising from the use of these circuits, software and information.
- While NEC endeavours to enhance the quality, reliability and safety of NEC semiconductor products, customers agree and acknowledge that the possibility of defects thereof cannot be eliminated entirely. To minimize risks of damage to property or injury (including death) to persons arising from defects in NEC semiconductor products, customers must incorporate sufficient safety measures in their design, such as redundancy, fire-containment, and anti-failure features.
- NEC semiconductor products are classified into the following three quality grades:
  "Standard", "Special" and "Specific". The "Specific" quality grade applies only to semiconductor products developed based on a customer-designated "quality assurance program" for a specific application. The recommended applications of a semiconductor product depend on its quality grade, as indicated below. Customers must check the quality grade of each semiconductor product before using it in a particular application.
  "Standard": Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots
  "Special": Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)
  "Specific": Aircraft, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems and medical equipment for life support, etc.
  The quality grade of NEC semiconductor products is "Standard" unless otherwise expressly specified in NEC's data sheets or data books, etc. If customers wish to use NEC semiconductor products in applications not intended by NEC, they must contact an NEC sales representative in advance to determine NEC's willingness to support a given application.
  (Note)
  (1) "NEC" as used in this statement means NEC Corporation and also includes its majority-owned subsidiaries.
  (2) "NEC semiconductor products" means any semiconductor product developed or manufactured by or for NEC (as defined above).

M8E 00.4